

# FDS4070N3

# 40V N-Channel PowerTrench® MOSFET

### **General Description**

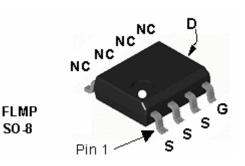
This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for "low side" synchronous rectifier operation, providing an extremely low  $R_{\text{DS(ON)}}$  in a small package.

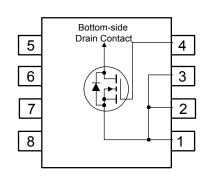
### **Applications**

- · Synchronous rectifier
- DC/DC converter

#### **Features**

- 15.3 A, 40 V.  $R_{DS(ON)} = 7.5 \text{ m}\Omega$  @  $V_{GS} = 10 \text{ V}$
- High performance trench technology for extremely low  $R_{\ensuremath{\mathsf{DS}}(\ensuremath{\mathsf{ON}})}$
- High power and current handling capability
- · Fast switching, low gate charge
- FLMP SO-8 package: Enhanced thermal performance in industry-standard package size





Absolute Maximum Ratings T<sub>A</sub>=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V <sub>DSS</sub>	Drain-Source Voltage		40	V
$V_{GSS}$	Gate-Source Voltage		± 20	V
I <sub>D</sub>	Drain Current - Continuous	(Note 1a)	15.3	Α
	– Pulsed		60	
P <sub>D</sub>	Maximum Power Dissipation	(Note 1a)	3.0	W
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range		-55 to +150	°C

### **Thermal Characteristics**

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	40	°C/W
R <sub>eJC</sub>	Thermal Resistance, Junction-to-Case	(Note 1)	0.5	

**Package Marking and Ordering Information** 

Device Marking	Device	Reel Size	Tape width	Quantity
FDS4070N3	FDS4070N3	13"	12mm	2500 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-Sc	ource Avalanche Ratings (Note	: 2)	I			u e
E <sub>AS</sub>	Drain-Source Avalanche Energy	Single Pulse, V <sub>DD</sub> =40V, I <sub>D</sub> =15.3A			310	mJ
I <sub>AS</sub>	Drain-Source Avalanche Current				15.3	Α
Off Char	acteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \qquad I_{D} = 250 \mu\text{A}$	40			V
$\Delta BV_{DSS} \over \Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, Referenced to 25°C		42		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 32 V, V <sub>GS</sub> = 0 V			1	μА
I <sub>GSSF</sub>	Gate–Body Leakage, Forward	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$			100	nA
$I_{\text{GSSR}}$	Gate–Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)					
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2	3.9	5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	$I_D$ = 250 μA, Referenced to 25 °C		-8		mV/°C
$R_{\text{DS(on)}}$	Static Drain–Source On–Resistance	$V_{GS} = 10 \text{ V}, I_D = 15.3 \text{ A}$ $V_{GS} = 10 \text{ V}, I_D=15.3 \text{A}, T_J=125 ^{\circ}\text{C}$		5.5 8	7.5 12	mΩ
<b>g</b> FS	Forward Transconductance	$V_{DS} = 10 \text{ V},  I_{D} = 15.3 \text{ A}$		52		S
Dynamic	Characteristics					
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 20 \text{ V},  V_{GS} = 0 \text{ V},$		2819		pF
C <sub>oss</sub>	Output Capacitance	f = 1.0 MHz		600		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			291		pF
Switchin	g Characteristics (Note 2)					
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = 20 \text{ V},  I_D = 1 \text{ A},$		16	29	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS}$ = 10 V, $R_{GEN}$ = 6 $\Omega$		12	22	ns
$t_{\text{d(off)}}$	Turn-Off Delay Time	7		41	66	ns
t <sub>f</sub>	Turn-Off Fall Time	7		29	46	ns
Qg	Total Gate Charge	$V_{DS} = 20 \text{ V},  I_{D} = 15.3 \text{ A},$		47	67	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 10 V		15		nC
$Q_{gd}$	Gate-Drain Charge	7		14		nC

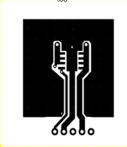
### **Electrical Characteristics**

 $T_A = 25^{\circ}C$  unless otherwise noted

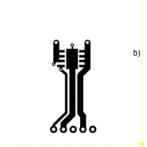
Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain–Source Diode Characteristics and Maximum Ratings						
Is	Maximum Continuous Drain–Source Diode Forward Current				2.5	Α
V <sub>SD</sub>	Drain–Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 2.5 A (Note 2)		0.7	1.2	V
t <sub>rr</sub>	Diode Reverse Recovery Time	I <sub>F</sub> = 15.3 A,		32		nS
Q <sub>rr</sub>	Diode Reverse Recovery Charge	$d_{iF}/d_t = 100 \text{ A/}\mu\text{s}$		39		nC

#### Notes

1. R<sub>0JA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>0JC</sub> is guaranteed by design while R<sub>0CA</sub> is determined by the user's board design.



a) 40°C/W when mounted on a 1in² pad of 2 oz copper



85°C/W when mounted on a minimum pad of 2 oz copper

Scale 1: 1 on letter size pape

**2.** Pulse Test: Pulse Width <  $300\mu$ s, Duty Cycle < 2.0

# **Typical Characteristics**

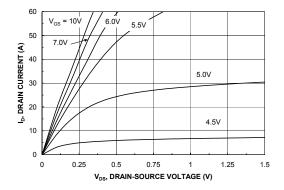


Figure 1. On-Region Characteristics.

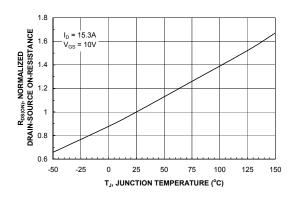


Figure 3. On-Resistance Variation withTemperature.

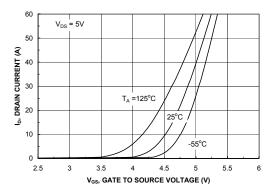


Figure 5. Transfer Characteristics.

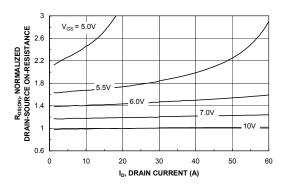


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

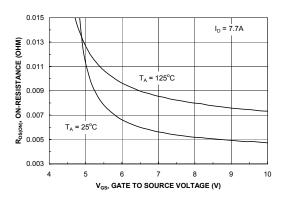


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

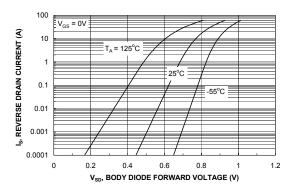
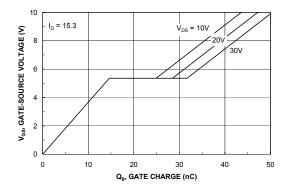


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

# **Typical Characteristics**



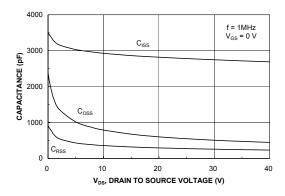


Figure 7. Gate Charge Characteristics.

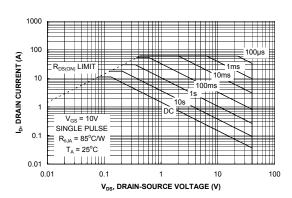


Figure 8. Capacitance Characteristics.

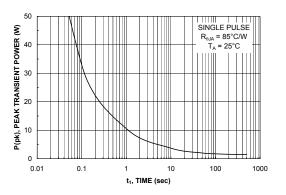


Figure 9. Maximum Safe Operating Area.



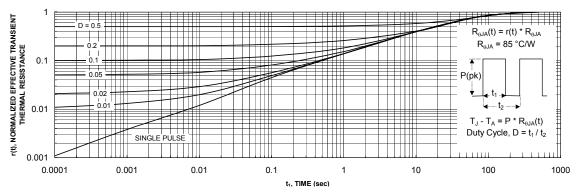
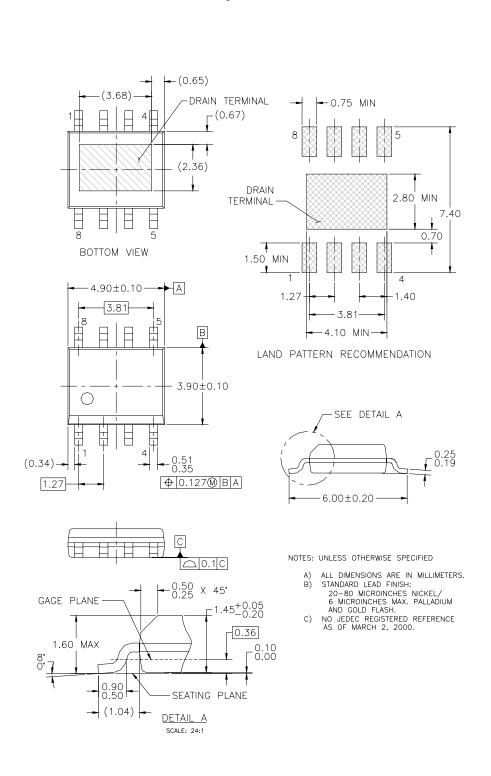


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

# **Dimensional Outline and Pad Layout**



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